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Application of Machine Learning in Big Data

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Deadline for manuscript submissions:

closed (31 August 2023)

Message from the Guest Editors

Dear Colleagues,

Currently, scalable machine learning architectures can provide faster fault detection to provide the services without interruption. However, there are several challenges of big data to be addressed, such as handling the continuous data growth problems, misperception with big data tool selection, securing data, integrating the data from several different sources, multi-dimensional and multi-variety data issues, etc. These issues can be addressed with properties of machine learning using deep learning, convolutional neural networks, supervised learning, unsupervised learning, reinforcement learning, etc. Thus, the main goal of this Special Issue is to invite high-quality submissions that should consist of original and novel research on the data-driven algorithms for big data, machine intelligence for big data, machine learning classifiers on big data for healthcare fast response, quantum-enhanced machine learning for IoT, drug discovery and toxicology in big data. Additionally, attention will be paid to several big data industry-driven machine learning algorithms.











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Message from the Editor-in-Chief

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